Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/687,085	MAEDA, HIROSHI
Examiner	Art Unit
Stephen W. Smoot	2813

SEARCHED				
Class	Subclass	Date	Examiner	
438	108	1/12/2005	sws	
438	118	1/12/2005	sws	
438	126	1/12/2005	sws	
438	127	1/12/2005	sws	
438	132	1/12/2005	sws	
438	601	1/12/2005	sws	
438	612	1/12/2005	sws	
438	613	1/12/2005	sws	
438	958	1/12/2005	sws	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	1.				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Key Words: Chip, Die, IC - Pad; Solder - Bump, Ball; Polyimide; Passivation; Fuse;	1/12/2005	J.V.S sws		
ChipCarrier, Package Substrate, Wiring Substrate; Flip Chip Assembly; Underfilled.	1/12/2005	L.W.S sws		
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Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	1/12/2005	I.V.J sws		